
**Optics and photonics — Measurement
of reflectance of plane surfaces
and transmittance of plane parallel
elements**

*Optique et photonique — Mesurage du facteur de réflexion des
surfaces planes et du facteur de transmission des éléments à plan
parallèle*

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Foreword

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This document was prepared by Technical Committee ISO/TC 172, *Optics and photonics*, Subcommittee SC 1, *Fundamental standards*.

This second edition cancels and replaces the first edition ISO 15368:2001 which has been technically revised. The main changes compared to the previous edition are as follows:

- Throughout the document, descriptions of the use of Fourier transform spectrometer instruments have been expanded and added where appropriate to an equivalent level as those of monochromator instruments.
- Throughout the document, the term “light” has been replaced with “optical radiation” to reflect that this standard’s spectral range extends beyond the visible.

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